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*Ashikhmin, A.; Kramer, G.; tenBrink, S.;*

 Information Theory, IEEE Transactions on , Volume: 50 , Issue: 11 , Nov. 200  
 Pages:2657 - 2673

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**2 The Simplex Codes and Other Even-Weight Binary Linear Codes for Error Correction**
*Helleseth, T.; Klove, T.; Levenshtein, V.I.;*

 Information Theory, IEEE Transactions on , Volume: 50 , Issue: 11 , Nov. 200  
 Pages:2818 - 2823

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IEEE JNL

**3 Subspace-Based Error and Erasure Correction with DFT Codes for Wireless Channels**
*Rath, G.; Guillemot, C.;*

 Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Processing, IEEE Transactions on] , Volume: 52 , Issue: 11 , Nov. 2004  
 Pages:3241 - 3252

[\[Abstract\]](#)
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IEEE JNL

**4 Soft-Input Reconstruction of Binary Transmitted Quantized Overcomplete Expansions**
*Kliewer, J.; Mertins, A.;*

 Signal Processing Letters, IEEE , Volume: 11 , Issue: 11 , Nov. 2004  
 Pages:899 - 903

[\[Abstract\]](#) [\[PDF Full-Text \(184 KB\)\]](#) IEEE JNL

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**5 Error-correction and crosstalk avoidance in DSM busses**

*Patel, K.N.; Markov, I.L.;*

Very Large Scale Integration (VLSI) Systems, IEEE Transactions on , Volume: 12 , Issue: 10 , Oct. 2004  
Pages:1076 - 1080

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**6 Identification of traitors in algebraic-geometric traceability codes**

*Fernandez, M.; Soriano, M.;*

Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Processing, IEEE Transactions on] , Volume: 52 , Issue: 10 , Oct. 2004  
Pages:3073 - 3077

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**7 Analyzing low-density parity-check codes on partial response channels with erasures using density evolution**

*Tan, W.; Cruz, J.R.;*

Magnetics, IEEE Transactions on , Volume: 40 , Issue: 5 , Sept. 2004  
Pages:3411 - 3418

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**8 Highly accurate measurement of sheet thickness: the planar error correction**

*Tojo, F.; Hirakawa, S.; Toyoda, T.; Yamagata, K.; Omura, A.; Maeji, Y.; Itoh, Applied Superconductivity, IEEE Transactions on , Volume: 14 , Issue: 2 , Jun 2004*

Pages:1810 - 1813

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**9 Stray field of a pulse septum induced by eddy currents**

*Shoji, Y.; Kumagai, K.;*

Applied Superconductivity, IEEE Transactions on , Volume: 14 , Issue: 2 , Jun 2004

Pages:441 - 444

[\[Abstract\]](#) [\[PDF Full-Text \(216 KB\)\]](#) IEEE JNL

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**10 Scalable image and video transmission using irregular repeat-accumulate codes with fast algorithm for optimal unequal error protection**

*Chingfu Lan; Tianli Chu; Narayanan, K.R.; Zixiang Xiong;*

Communications, IEEE Transactions on , Volume: 52 , Issue: 7 , July 2004  
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**11 Interpolation-free coregistration and phase-correction of airborne SAR images**

**interferograms***Prats, P.; Reigber, A.; Mallorqui, J.J.;**Geoscience and Remote Sensing Letters, IEEE , Volume: 1 , Issue: 3 , July 20*  
*Pages:188 - 191*[\[Abstract\]](#) [\[PDF Full-Text \(240 KB\)\]](#) [IEEE JNL](#)**12 Residential microwave oven interference on Bluetooth data performance***Rondeau, T.W.; D'Souza, M.F.; Sweeney, D.G.;**Consumer Electronics, IEEE Transactions on , Volume: 50 , Issue: 3 , Aug. 20*  
*Pages:856 - 863*[\[Abstract\]](#) [\[PDF Full-Text \(553 KB\)\]](#) [IEEE JNL](#)**13 Design of stable IIR digital filter based on least P-power error crite***Chien-Cheng Tseng;**Circuits and Systems I: Regular Papers, IEEE Transactions on [see also Circuit*  
*Systems I: Fundamental Theory and Applications, IEEE Transactions on] , Vol*  
*51 , Issue: 9 , Sept. 2004*  
*Pages:1879 - 1888*[\[Abstract\]](#) [\[PDF Full-Text \(632 KB\)\]](#) [IEEE JNL](#)**14 High-throughput error correcting space-time block codes***Martin, P.A.; Taylor, D.P.;**Communications Letters, IEEE , Volume: 8 , Issue: 7 , July 2004*  
*Pages:458 - 460*[\[Abstract\]](#) [\[PDF Full-Text \(184 KB\)\]](#) [IEEE JNL](#)**15 Design of flexible-length S-random interleaver for turbo codes***Popovski, P.; Kocarev, L.; Risteski, A.;**Communications Letters, IEEE , Volume: 8 , Issue: 7 , July 2004*  
*Pages:461 - 463*[\[Abstract\]](#) [\[PDF Full-Text \(144 KB\)\]](#) [IEEE JNL](#)

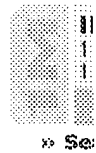
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**1 Area efficient parallel decoder architecture for long BCH codes**
*Yanni Chen; Parhi, K.K.;*

Acoustics, Speech, and Signal Processing, 2004. Proceedings. (ICASSP '04). II International Conference on , Volume: 5 , 17-21 May 2004

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**2 FPGA based realization of a reduced complexity high speed decoder error correction**
*Abbasi, S.A.;*

Electronics, Circuits and Systems, 2003. ICECS 2003. Proceedings of the 2003 IEEE International Conference on , Volume: 3 , 14-17 Dec. 2003

Pages:1002 - 1005 Vol.3

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**3 Fast, minimal decoding complexity, system level, binary systematic 32) single-error-correcting codes for on-chip DRAM applications**
*Amir, K.; Eric, B.;*

Defect and Fault Tolerance in VLSI Systems, 2001. Proceedings. 2001 IEEE International Symposium on , 24-26 Oct. 2001

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**4 A combined Reed-Solomon encoder and syndrome generator with sr hardware complexity**
*Fettweis, G.; Hassner, M.;*

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